

Search Notes	Application/Control No.	Applicant(s)/Patent Under Reexamination
	10593424	RITTER ET AL.
Examiner	Art Unit	
Hai Phan	2614	

SEARCHED

Class	Subclass	Date	Examiner
381	381, 327, 110, 56, 57, 71.1, 92, 94.1	10/05/10	HP

SEARCH NOTES

Search Notes	Date	Examiner
Inventor Search	10/05/10	HP
EAST Search	10/05/10	HP
Update Search	03/21/11	HP
Update Search	09/24/11	HP

INTERFERENCE SEARCH

Class	Subclass	Date	Examiner

	/HAI PHAN/ Primary Examiner.Alt Unit 2614
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